# The hardware interfaces of the CCB

Martin Shepherd, California Institute of Technology

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#### Abstract

This document specifies the operational characteristics of the CCB hardware interfaces.

# Contents

1	A d	efinition of terms	4
<b>2</b>	Dat	a-type conventions	4
	2.1	Integer parameters	4
	2.2	Boolean parameters	4
3	The	PCI interface between the computer and the FPGA	<b>5</b>
	3.1	Configuration registers	5
		3.1.1 Detailed descriptions	6
	3.2	The control register	9
		3.2.1 Detailed descriptions	9
	3.3	Diagnostic monitoring registers	11
		3.3.1 Detailed descriptions	11
	3.4	Data output via DMA	12
	3.5	Interrupts	12
		3.5.1 Detailed descriptions	13
	3.6	The interrupt status registers	13
		3.6.1 Detailed descriptions	13
4	Joh	n's FPGA state diagrams	13

# List of Figures

1	A summary of the structure of a scan	14
2	The hardware timers	15
3	The integration state machine	16
4	The sample state machine	17

# 1 A definition of terms

The following terms are used throughout this document. It is recommended that in other documents that describe both the hardware and software, these terms be prefixed with the word *hardware* when referring to the FPGA.

#### • A sample

A single A/D sample.

#### • A measurement

The group of samples added within a single phase-switch state of a single cycle.

#### • A cycle

A single phase-switch cycle is composed of between 1 and 32 samples, with each sample individually programmable to have 1 of 4 possible phase switch states.

#### • integration period

The integer number of cycles who's measurements are to be coadded to form integrations.

#### • An integration

The data accumulated for a single phase switch state during an integration period.

#### • A scan

A group of one or more integrations associated with a single set of scan-specific configuration parameters.

# 2 Data-type conventions

## 2.1 Integer parameters

Integer valued parameters presented over the PCI bus are unsigned and arranged in littleendian byte order.

## 2.2 Boolean parameters

Boolean registers presented over the PCI bus are represented as single bits within larger data-types. The ordering of the bits within these data-types is defined such that performing a logical shift right by 1 bit, results in the successively next least significant bit appearing on the carry line of the shift register. The meanings of the values of these bits are as follows:

	0	1
Boolean	false	true
Switch state	off	on

Note that when referring to phase-switches, **off** corresponds to when the phase-shifter isn't inserting any phase-shift into the signal path, and **on** means that it is inserting a  $180^{\circ}$  phase shift.

# 3 The PCI interface between the computer and the FPGA

# 3.1 Configuration registers

The values of the following registers are examined by the FPGA just before starting each new integration, and are therefore written by the device driver in advance of the start of each new integration.

The device driver adopts the following strategies to ensure that the values of these registers are updated in advance of each new integration.

- The FPGA sends the device driver an interrupt just after ending one integration and loading the configuration of the following integration. On receiving this interrupt, the device driver updates the configuration registers with the configuration of the integration that follows the one that is just being started.
- Whenever the FPGA is reset, the device driver writes the configuration of the first integration before interrupts are enabled. Since the FPGA doesn't start its state machine until interrupts are first enabled, this ensures that the parameters of the first integration are configured before the FPGA loads them.
- When directing the FPGA to start a new scan, the driver first asserts the start-scan bit in the control register, updates the configuration registers with the configuration of the first integration of the scan, then allows the new scan to start by deasserting the start-scan bit.

Note that in practice, very few of the configuration registers change from one integration to the next. In fact, except at the start of a new scan, usually only the calibration diode registers change from one integration to the next.

Name	Description	Qty	Multiplier	Default	Range
samples-per-cycle	Samples per cycle	1	1 sample	1	1-32
phase-switch-a	The on/off state of phase switch A	32	boolean	0	0  or  1
phase-switch-b	The on/off state of phase switch B	32	boolean	0	0  or  1
cycles-per-integ	Integration period	1	1 cycle	40	1-65535
long-sample-dt	Long sample interval	1	$0.1 \mu { m s}$	250	1-65535
short-sample-dt	Short sample interval	1	$0.1 \mu \mathrm{s}$	250	1-65535
phase-switch-dt	Phase-switch blanking interval	1	$0.1 \mu { m s}$	0	1 - 255
analog-reset-dt	Integrator-reset blanking interval	1	$0.1 \mu \mathrm{s}$	0	1 - 255
cal-diode-states	Calibration diode on/off states	2	boolean	0	0  or  1
cal-diode-dt	Calibration diode settling time	1	$0.1 \mu { m s}$	0	$1 - 2^{32} - 1$

#### 3.1.1 Detailed descriptions

#### • Samples per cycle (samples-per-cycle)

The states of the phase-switch within each stage of the phase-switch cycle are configured via a 32 stage state-machine, advanced by one state every time that a new sample is taken by the A/D. In practice only the first samples-per-cycle of these states is used.

Note that while the direct specification of a 32-state state machine allows a great deal of flexibility, in practice the states are filled by the device driver from much higher level configuration parameters, such as the number of samples per measurement, the selection of one of 3 phase-switching modes (ie. no phase-switching, 1-diode phase-switching, 2-diode phase-switching), and the specified initial states of the phase switches at the start of each cycle.

#### • The state of phase switch A (phase-switch-a)

Each bit of this 32-bit register specifies the state of phase-switch A in both radiometers, at one stage of the phase-switching state machine. This is designed to be loaded into a 32-bit shift register at the start of each phase-switch cycle, then right shifted just before the start of each new sample, to determine the required state of the phase switches in that sample. The number of shifts required to complete a cycle is determined by the samples-per-cycle register described above.

• The state of phase switch B (phase-switch-b)

This register is the same as the **phase-switch-a** register, except that it is applied to phase-switch B instead of to phase-switch A.

#### • Integration period (cycles-per-integ)

This is the integer number of complete phase-switch cycles who's measurements are to be integrated, before presenting the data to the computer. It was decided at the preliminary design review that 1ms is the minimum integration time that needs to be guaranteed. In practice, shorter times may also be possible, depending on the speed of the computer, the bandwidth of the PCI bus, and the bandwidth of the communications link between the CCB server and the CCB manager.

#### • Long sample interval (long-sample-dt)

This is the time spent integrating individual A/D samples that aren't preceded by phase switch transitions. This interval does not include the time spent resetting the analog integrators.

Although this interval is widely configurable, the analog electronics are designed for a sampling interval of  $25\mu$ s, so longer intervals may result in the A/D saturating, and much shorter intervals may not be possible with the chosen ADC.

#### • Short sample interval (short-sample-dt)

This is the time spent integrating A/D samples that are preceded by phase switch transitions. The device driver gives this register the value,

short-sample-dt = long-sample-dt - phase-switch-dt 
$$(1)$$

As explained later, in cycles that don't contain any phase-switch transitions, phase-switch-dt is zero, so the value of short-sample-dt register is then be equal to long-sample-dt.

#### • Phase switch blanking interval (phase-switch-dt)

This is the settling time needed by the phase-switches in the front-end whenever they change state. The FPGA inserts this delay, both whenever it changes the states of the phase switches, and for the first sample of each cycle. It is important to understand the interaction between this register and the **phase-switch-b** and **phase-switch-a** registers, since it is possible to generate flawed cycles. The basic constraints are:

- 1. The total integration time spent in each phase-switch state of a cycle must be identical. Otherwise the equations governing the operation of the differential radiometer would be broken.
- 2. Settling time delays must be inserted as needed to prevent phase-switch transitions corrupting the integrated data.
- 3. As few delays should be included as possible, to avoid wasting integration time.

The main difficulty in complying with these constraints is that the phase-switch states are un-predictable to the driver for the first sample of each new scan, and completely unknown by the FPGA before the first scan after a FPGA reset (eg. at power-on). Thus if one just went by the rule that delays should be included at phase-switch transitions, there might or might not be a delay removed from the first sample of a new cycle, and in the first scan there might not be a delay included when a delay was needed. This would randomly break the first and second of the constraints listed above. The way to correct these problems depends on the type of phase-switching cycle being commanded, as follows. The basic approach is to require an equal number of samples in each of the phaseswitch states of the cycle, and require that all samples within a given phase-switch state are contiguous in the cycle. This requirement is enforced by the device driver. The consequences of this strategy, and the minor adjustments that are required to work around its deficiencies are as follows.

- In cycles that include at least one phase-switch transition, the above strategy ensures that there is exactly one phase-switch transition per phase-switch state, and thus that the same amount of time is lost to phase-switching in each phaseswitch state. A exception to this rule is at the start of a scan, where this strategy might or might not cause a phase-switch delay to be included, depending on what state the previous scan left the phase-switches in. For this reason, the FPGA state machine always includes a phase-switching delay at the start of each cycle, irrespective of whether a phase-switch transition occurred or not.
- In cycles where the phase-switch states are held in a single unchanging state, there are no phase-switch transitions, and thus no need for phase-switching delays. Since the FPGA always includes a phase-switch delay at the start of each cycle, it is thus necessary for the device-driver to set phase-switch-dt to zero for unswitched cycles. Again, depending on what state the previous scan left the phase-switches in, there may need to be a phase-switch transition before the first cycle can procede. In order not to break the first of the constraints, this delay needs to be removed before the first cycle starts, rather than being subtracted from the first sample of the first cycle. To handle this, the device driver lengthens, if necessary, the value of cal-diode-dt of the first integration of the scan, to include one phase-switch transition delay.

#### • Integrator reset blanking interval (analog-reset-dt)

This specifies how much time is needed to reset the analogue integrators to zero. The choice of this number is determined by the current-handling capacity of both the capacitors and the FET switches that are used to discharge them, and should be around  $0.5\mu$ s. This delay is inserted after each A/D sample.

#### • Cal diode states (cal-diode-states)

The 2 least-significant bits of this register specify the states that the noise diodes are to be set to at the start of the next integration period. A value of 1 means turn a diode on; a value of 0 means turn it off. This is updated by the device driver from the integration-done ISR.

#### • Calibration diode settling time (cal-diode-dt)

The calibration diodes are potentially switched at the start of each new integration period. This register specifies how long the hardware must wait after commanding the diodes to their new states, before starting the first sample of the following integration. Its value, which is set by the integration-done ISR before each integration, is determined according to the following rules.

- If neither calibration diode is changing state, then the driver writes zero in this register.
- If one or both of the diodes is being switched on, and neither are being switched off, then the driver writes the cal-diode rise time in this register.
- If one or both of the diodes is being switched off, and neither are being switched on, then the driver writes the cal-diode fall time in this register.
- If one of the diodes is being switched off, and the other is being switched on, then the driver writes the longest of the cal-diode rise and fall times in this register.
- If the integration is the first integration of a scan, then the driver writes the longest of the phase-switch and cal-diode rise and fall times in this register.

Note that the 32-bit range of this register is bigger than that of any other timer. This is due to the uncertainty over how long the diodes need to settle to a level suitable for astronomical measurements.

## 3.2 The control register

This register is a 32-bit register who's individual bits set flags in the hardware. The first thing that the FPGA does after being reset, is to zero the bits in this register. It then waits for the driver to set the interrupt-enable bit in this register before starting its state machine. This gives the driver the chance to initialize the configuration registers to suitable values for the first integration of the first scan.

Bit	Name	Description	Effect
0	start-scan	Start a new scan	Start a new scan at the end of the current sample
1	wait-1pps	Scan starts on 1-PPS	Synchronize scan starts with 1-PPS?
2	reset-fpga	Reload FPGA firmware	Reload the FPGA firmware from EPROM
3	interrupt-enable	Enable interrupts	Enable 1-PPS and integration interrupts
4	drive-phs-a	Drive phase-switch A	Drive phase-switch A's control line
5	drive-phs-b	Drive phase-switch B	Drive phase-switch B's control line
6	drive-cal-a	Drive cal-diode A	Drive cal-diode A's control line
7	drive-cal-b	Drive cal-diode B	Drive cal-diode B's control line

The operations listed in the above table are all asserted by setting the corresponding bits to 1 (ie. positive assertion logic). The response of the hardware to each of these bits is detailed below.

#### 3.2.1 Detailed descriptions

• Start scan (start-scan)

Asserting this bit immediately resets the integration state machine in the FPGA, thus returning it to its starting state. Subsequently deasserting this bit starts the integration state machine. Between asserting and deasserting this bit, the device driver sends the FPGA the configuration of the first integration of the scan.

When the device driver finishes writing the new configuration, it deaserts the startscan bit. The FPGA then latches the integration configuration registers and starts to drive both the cal-diode and the phase-switch lines to their initial states. It then examines the wait-1pps bit of the control register, and if this is asserted, the FPGA waits for the next rising edge of the 1-PPS signal before proceeding with the integration state machine.

Within the device driver, this bit is used to implement the start-data-scan and start-intra-scan commands, as follows.

#### start-data-scan:

- 1. Assert the start-scan bit in the control register.
- 2. Assert the wait-1pps bit in the control register.
- 3. Update the hardware configuration registers to configure the first integration.
- 4. Wait for the next 1-PPS interrupt.
- 5. If the timestamp of the 1-PPS is more than one second before the requested start time, go back to step 4.
- 6. Deassert the start-scan bit in the control register.

#### start-intra-scan:

- 1. Assert the start-scan bit in the control register.
- 2. Deassert the wait-1pps bit in the control register.
- 3. Update the hardware configuration registers to configure the first integration.
- 4. Deassert the start-scan bit in the control register.

Since the states of the calibration diodes and the phase-switches aren't known by the device driver at the instant that the **start-scan** bit is asserted, and the timing of integrations needs to be predictable to the manager, the device driver sets the value of the **cal-diode-dt** register for the first integration to the longest of the phase-switch and cal-diode rise and fall times. This causes the FPGA to wait for this amount of time before starting to integrate the first sample, and thus gives the calibration diodes and the phase-switches time to settle.

## • Reload FPGA firmware (reset-fpga)

This bit is asserted by the driver at startup, and can also be used during initial debugging to reload the FPGA program from EPROM after a crash. After a reload, the FPGA zeroes the control register, then waits for the device-driver to assert the interrupt-enable bit of this register before initiating the first scan.

#### • Enable interrupts (interrupt-enable)

Whenever the FPGA is reset, the generation of 1-PPS and integration interrupts is initially disabled. This bit is used to enable them once the driver is in a fit state to respond to them. Subsequently setting it to zero simply stops interrupts from being generated, without affecting the rest of the state machine.

#### • Drive phase-switch A (drive-phs-a)

This bit turns on the output control line which drives phase-switch A.

#### • Drive phase-switch B (drive-phs-b)

This bit turns on the output control line which drives phase-switch B.

#### • Drive cal-diode A (drive-cal-a)

This turns on the output control line which drives calibration diode A.

## • Drive cal-diode B (drive-cal-b)

This turns on the output control line which drives calibration diode B.

# 3.3 Diagnostic monitoring registers

These registers, which are stored in PCI DMA memory, are updated by the hardware just before the integration-done interrupt is sent. The device driver thus reads them out on receipt of this interrupt.

Description	Qty	Units	Range
Power supply voltages	N/A	mv	N/A
A/D converter outputs	16	A/D sample	$0\cdots 2^{32}-1$

The ordering of the array of 16 A/D converter outputs is as follows.

Array Index	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15
Detector	1	2	1	2	1	2	1	2	1	2	1	2	1	2	1	2
Band 1		$2\dots  3\dots  4$					$4\ldots  1\ldots  2\ldots$				3 4					
Radiometer	1.	1							2							

## 3.3.1 Detailed descriptions

#### • Power supply voltage

This records the voltages of all power supplies in the system. 8 bits should provide ample precision for these values.

#### • A/D converter outputs

The last values read-out from the 16 A/D converters. This can be used to check for failing A/D converters and A/D saturation. Like the A/D converters themselves, these are 16-bit values.

# 3.4 Data output via DMA

Like the diagnostic monitoring registers, these registers are stored in PCI DMA memory, and are updated by the hardware just before the integration-done interrupt is sent. The device driver thus reads them from DMA memory on receipt of this interrupt.

Description	Qty	Units	Range
An integrated data value	64	_	$0 \cdots 2^{32} - 1$
Overflow mask	64	boolean	0 or 1

The overflow mask uses 64 bits of an array of 8 bytes to record which of the 64 data values suffered overflows during integration. Bits are numbered from zero, starting with the least significant bit of the highest memory location, and ending at 63 with the most significant bit of the lowest memory location.

The array of integrations is arranged as an array of 32-bit little-endian integers, indexed from zero, starting with the element in the lowest memory location.

The order of assignment of the 64 values and their corresponding overflow bits to array indexes and bit indexes is as follows.

Array index	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17
Integration	1	2	3	4	1	2	3	4	1	2	3	4	1	2	3	4	1	2
Detector	Detector $1 \dots \dots$				2.	2			1				2				1	•••
Band	1												3					
Radiometer	1				•••		•••	•••										

# 3.5 Interrupts

The following interrupts share a single interrupt line.

Description	When the interrupt
Integration interrupt	When one integration ends and another has just been started.
1-PPS interrupt	On rising edges of the 1-PPS signal

#### 3.5.1 Detailed descriptions

#### • Integration interrupt

This interrupt serves two purposes.

- 1. It tells the driver that the results of the last integration period have just been written to the DMA memory area, and that the driver should read them ASAP.
- 2. It tells the driver that the configuration registers should be updated to configure the integration that follows the one that has just been started.

Immediately before generating this interrupt, the FPGA sets the sent-integ-done register to 1.

#### • 1-PPS interrupt

Whenever a rising edge of the 1-PPS signal is seen, the FPGA first sets the 1-PPS sent-1pps register, then generates this interrupt.

#### 3.6 The interrupt status registers

The following interrupt status registers are checked by the device driver whenever it receives an interrupt. It uses them to check which event or events generated the interrupt, and responds accordingly. Note that to prevent race conditions in the device driver when it comes to resetting these registers, it is essential that they be separate registers, rather than individual bits within a single register.

Name	Description
sent-1pps	1-PPS interrupt sent
sent-integ-done	End-of-integration interrupt sent

#### 3.6.1 Detailed descriptions

#### • End-of-integration interrupt sent (sent-integ-done)

Immediately before the FPGA sends an integration interrupt, it sets this register to 1. The device-driver's interrupt handler subsequently resets it to zero.

#### • 1-PPS interrupt sent (sent-1pps)

Immediately before the FPGA sends a 1-PPS interrupt, it sets this register to 1. The device-driver's interrupt handler subsequently resets it to zero.

# 4 John's FPGA state diagrams

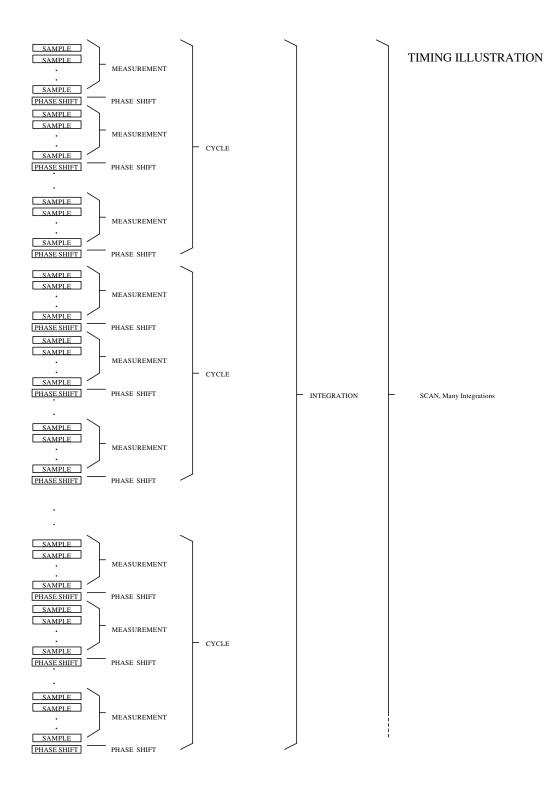


Figure 1: A summary of the structure of a scan

#### STATE TIMERS

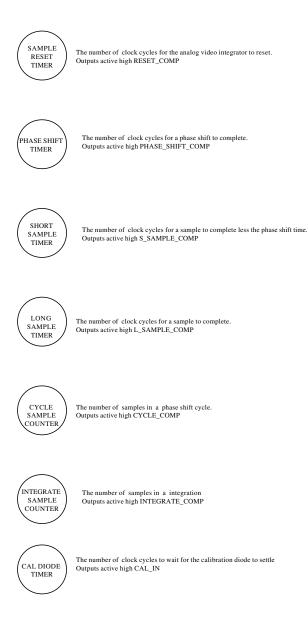
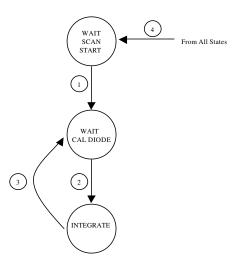


Figure 2: The hardware timers

#### INTEGRATE STATE MACHINE



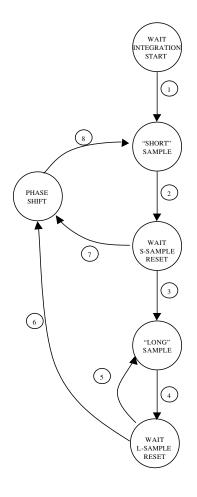
State Definitions: WAIT SCAN START INTEGRATE REG SOURCE WAIT CAL DIODE

Wait here until a scan start comes Integrating on source Wait here until the Calibration Diode is in wrote to "PING" registers

STATE TRANSITIONS: 1. (START\_SCAN &:START\_IPPS) # (START\_SCAN & START\_IPPS & IPPS) 2. CAL\_DIODE\_SETTLED 3. INT\_COMPLETE & CAL\_DIODE\_CHANGE 4. !START\_SCAN

Figure 3: The integration state machine

#### SAMPLE STATE MACHINE



State Definitions: WAIT INTEGRATION START "SHORT SAMPLE" WAIT S-SAMPLE RESET PHASE SHIFT "LONG" SAMPLE WAIT L-SAMPLE RESET

State Transitions: 1.INTEGRATE 2.S.SAMPLE\_COMP 3.RESET\_COMP & IPHASE\_SHIFT 4.L\_SAMPLE\_COMP 5.RESET\_COMP & IPHASE\_SHIFT 6.RESET\_COMP & IPHASE\_SHIFT 7.RESET\_COMP & IPHASE\_SHIFT 8.PHASE\_SHIFT\_COMP Wait here for the integration to start Sample time minus time for phase shift Wait for reset time for "SHORT" sample. Time for phase shift to complete Sample time no phase shift between samples Wait for reset time for "LONG" sample

Figure 4: The sample state machine